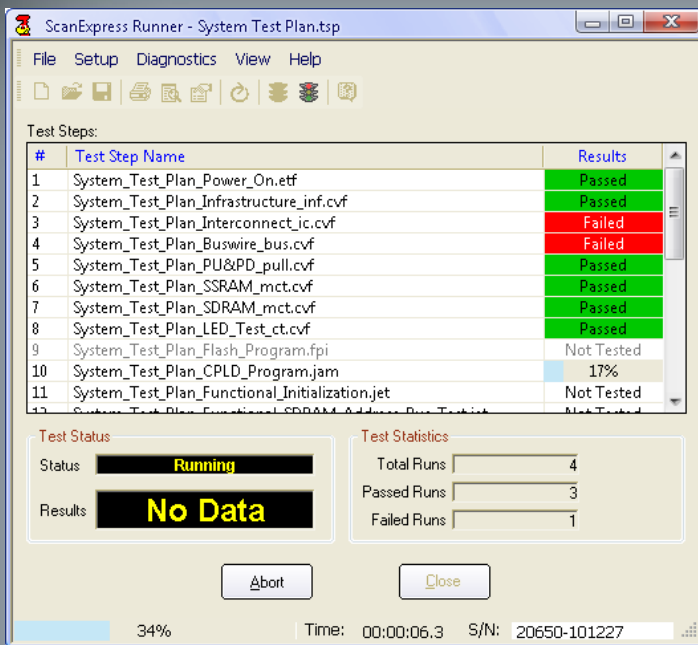


ScanExpress Runner™

CORELIS
An EWA Company

Boundary-Scan Test Executive

Preferred Boundary-Scan Test Solutions—Acclaimed Technical Support



Features

- Built-in test sequencer that automatically and dynamically executes independent test steps
- Intelligent fault detection and isolation to the net and pin level
- Truth Table Diagnostics with pattern and waveform views
- Integrated test debugger including breakpoints, looping, and single-step capability
- User-programmable general purpose parallel input/output (GPIO) signal control
- In-System-Programming (ISP) of CPLDs, Flash memories and serial EEPROM devices
- Executes JTAG Embedded Test (JET) steps for extended test coverage and embedded functional testing
- Interfaces with LabVIEW, LabWindows/CVI, Agilent VEE, Visual Basic, and other third party test executives
- Supports Corelis high-performance JTAG controllers
- Compatible with the Corelis ScanExpress family of products
- Works with Windows XP, Windows Vista, and Windows 7

Efficiency in engineering means managing your most precious resources: time and effort. Automated testing is a given and boundary-scan is an essential component; no other structural test system provides the same value.

When down to the wire, your boundary-scan test system needs to be built both for ease-of-use and reliability; a robust and powerful mechanism to ensure that no matter the state of production, all boundary-scan tests can be quickly and faithfully executed to maintain forward momentum.

ScanExpress Runner™ is a fully featured JTAG test executive; a modern software application that provides the capabilities and options necessary to ensure a smooth and complete testing process. With visual, one-touch execution of ScanExpress test sequences and interface support for all major test platforms, ScanExpress Runner stands proud as the reliable daily workhorse of the ScanExpress family.

Benefits

- Enables boundary-scan test, in-system programming, and JET functional test
- Simplifies boundary-scan test execution
- Increases yields and decreases test time
- Speeds test, diagnosis, and repair of faulty circuit boards

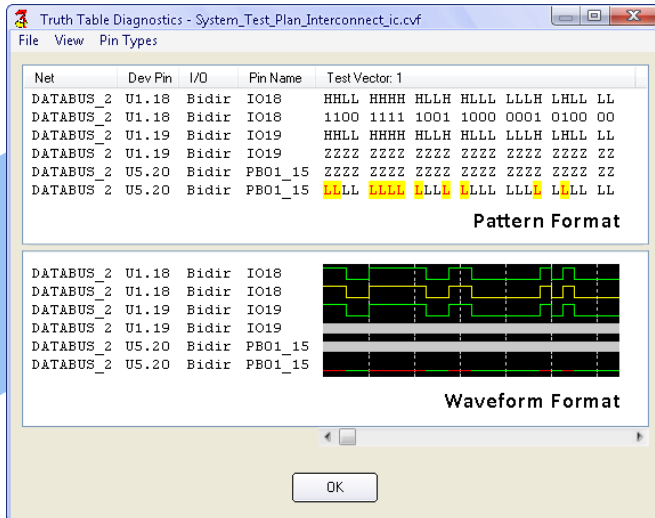
Applications

- **Hardware Development**—Use boundary-scan to test, debug, and verify prototype hardware, then reuse the same tests for full-scale production.
- **Hardware Production**—The graphical user interface is both straightforward and powerful, enabling execution of complete tests with the click of a button.
- **Service & Repair**—Re-use the same tests from development and production to reduce troubleshooting and repair times.

Learn More: For more information about Corelis products, please visit www.corelis.com

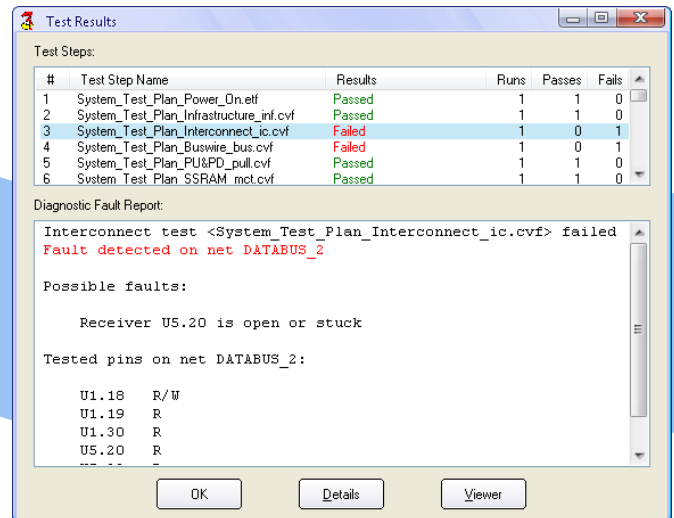
The ScanExpress Runner™ test executive enables execution of IEEE-1149.1 (JTAG) boundary-scan tests with an easy-to-use graphical user interface (GUI) and advanced test execution features. Runner comes standard with Basic Diagnostic (BDO) functionality and can be enhanced with the optional Advanced Diagnostics (ADO) module for detailed pin and net level diagnostics.

Basic Diagnostics



Basic Diagnostics (BDO) module displays complete Truth Table Diagnostic test results in pattern or waveform format.

Advanced Diagnostics



Advanced Diagnostics (ADO) module adds detailed descriptions of detected faults down to the pin and net level.

Combined Structural and Functional Test with ScanExpress TPG and JET

ScanExpress Runner can be utilized to execute both boundary-scan structural test steps generated by ScanExpress TPG™ and functional tests created by ScanExpress JET™, enabling a holistic approach to JTAG-based non-intrusive test. Whether on the desktop, test bench, or in the field, a complete JTAG test strategy can be achieved with just a host PC, Corelis JTAG controller, and ScanExpress Runner execution software¹.

Third Party Application Support

In addition to the intuitive operator interface, ScanExpress Runner includes a third party application interface consisting of DLLs, command-line functions, and LabVIEW virtual instrument drivers. ScanExpress Runner integrates easily and conveniently into off-the-shelf test executive solutions and custom, in-house software solutions alike.

Test File Formats

ScanExpress Runner supports a multitude of input file formats created by Corelis boundary-scan tools as well as third party vector generators. Supported test step file formats include the following:

- **Compact Vector Format (CVF)** — ScanExpress TPG™ generated test step files for world class boundary-scan tests.
- **JTAG Embedded Test (JET)** — ScanExpress JET™ test step files for JTAG-based functional tests.
- **Flash Programming Information (FPI)** — ScanExpress Flash Generator™ files for Flash and EEPROM in-system programming.
- **Serial Vector Format (SVF) & Standard Test and Programming Language (STAPL)** — Standard vector files for FPGA and CPLD programming.
- **Extensible Test Format (ETF)** — Script-based test steps for utility functions and interfacing with third party command-line applications.

Ordering Information

Part Number—20650

CORELIS

13100 Alondra Blvd.
Cerritos, CA 90703, USA
Phone: +1 888-808-2380 (US & Canada)
Phone: +1 562-926-6727 (International)
Fax: +1 562-404-6196
www.corelis.com

¹ScanExpress JET test step execution requires a JET family support package license.

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